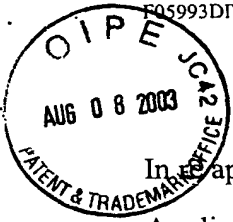


COPY



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Ushio *et al.*

Art Unit: 2818

Application No. 09/881,445

Confirmation No. 7027

Filed: June 13, 2001

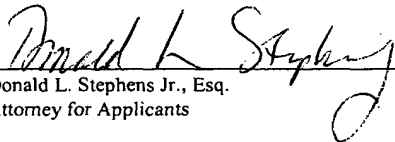
CERTIFICATE OF MAILING

For: LAYER-THICKNESS DETECTION
METHODS AND APPARATUS FOR
WAFERS AND THE LIKE, AND
POLISHING APPARATUS

I hereby certify that this paper and the documents referred to as being attached or enclosed herewith are being deposited with the United States Postal Service on August 6, 2003, as First Class Mail in an envelope addressed to: COMMISSIONER FOR PATENTS, P.O. BOX 1450, ALEXANDRIA, VA 22313-1450.

Examiner: Not yet assigned

Date: August 6, 2003


Donald L. Stephens Jr., Esq.
Attorney for Applicants

TRANSMITTAL LETTER

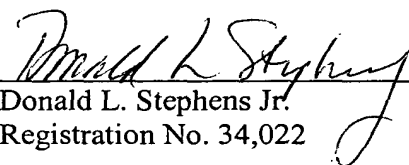
COMMISSIONER FOR PATENTS
P.O. BOX 1450
ALEXANDRIA, VA 22313-1450

Enclosed for filing in the application referenced above are the following:

- ☒ Supplemental Information Disclosure Statement
- ☒ Form 1449 and copies of the 23 references cited thereon
- ☒ The Director is hereby authorized to charge any additional fees that may be required, or credit over-payment, to Deposit Account No. 02-4550. A copy of this sheet is enclosed.
- ☒ Please return the enclosed postcard to confirm that the items listed above have been received.

Respectfully submitted,

KLARQUIST SPARKMAN, LLP

By 
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cc: Docketing